

In situ tensile deformation of silicon doped $\text{Fe}_{50-x}\text{Mn}_{30}\text{Co}_{10}\text{Cr}_{10}\text{Si}_x$ high entropy alloy

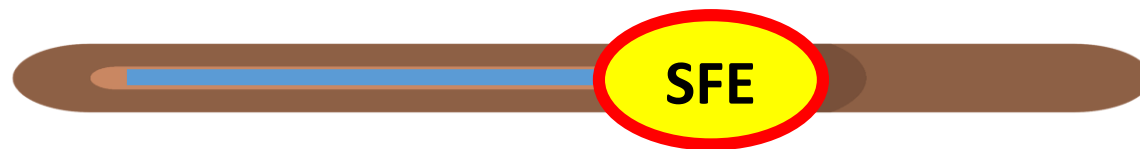


Roopam Jain*, Mirtunjay Kumar, Krishanu Biswas and N P Gurao

Department of Materials Science and Engineering
Indian Institute of Technology Kanpur, Kanpur - 208016, India

Deformation mechanism = f (stacking fault energy)

Stacking fault energy = f (alloying elements)

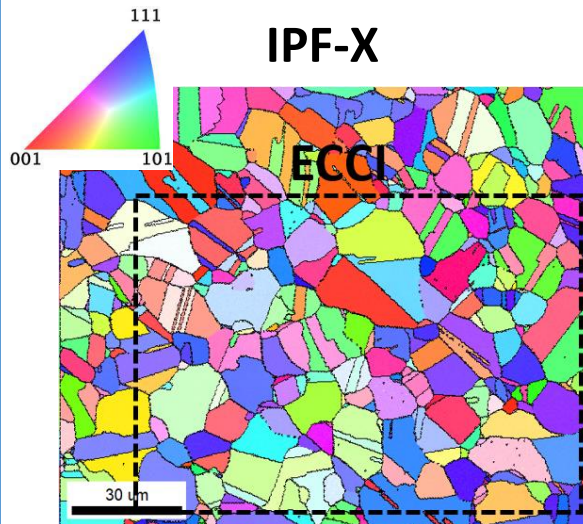


TRIP → TWIP → Planar slip



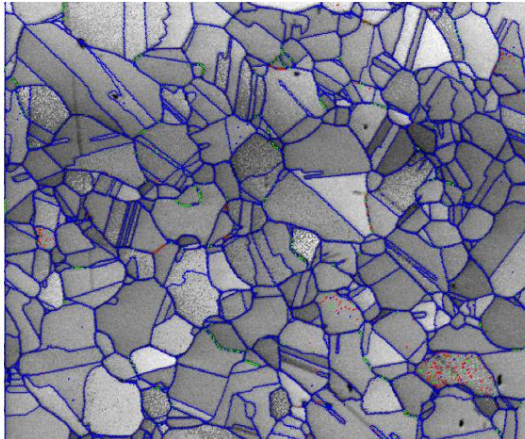
Initial Microstructure after Si doping

Results & Discussion

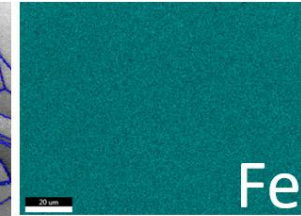


IPF-X

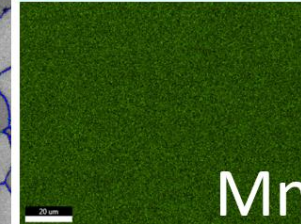
Boundary map (15-180)



EDS maps



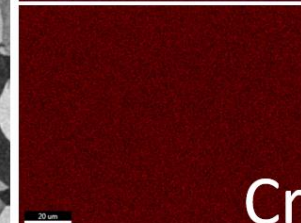
Fe



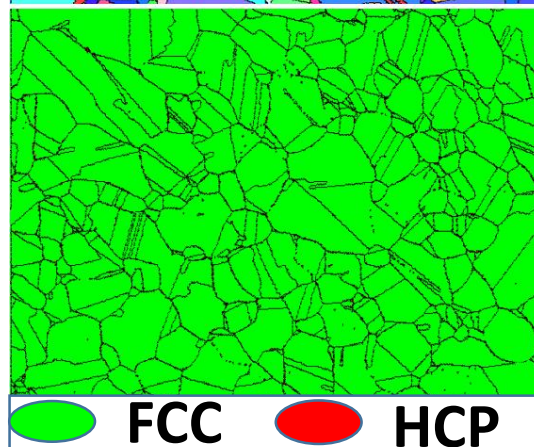
Mn



Co

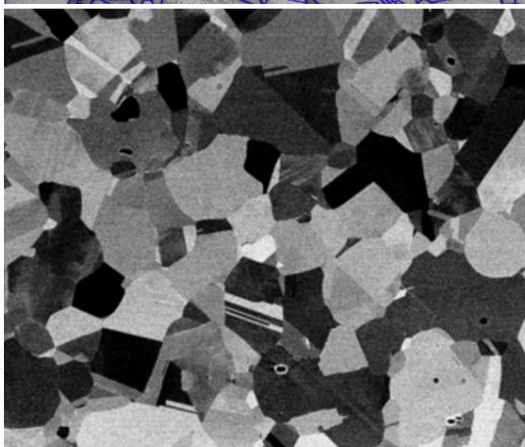


Cr



● FCC ● HCP

Phase map



ECCL micrograph

Wet chemical analysis

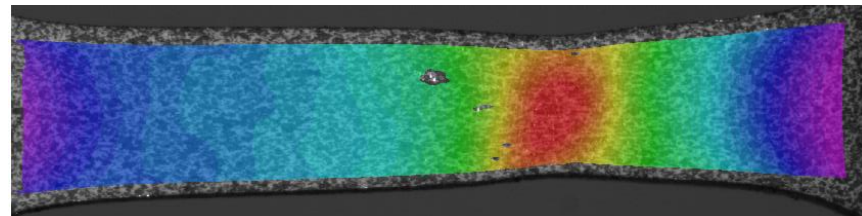
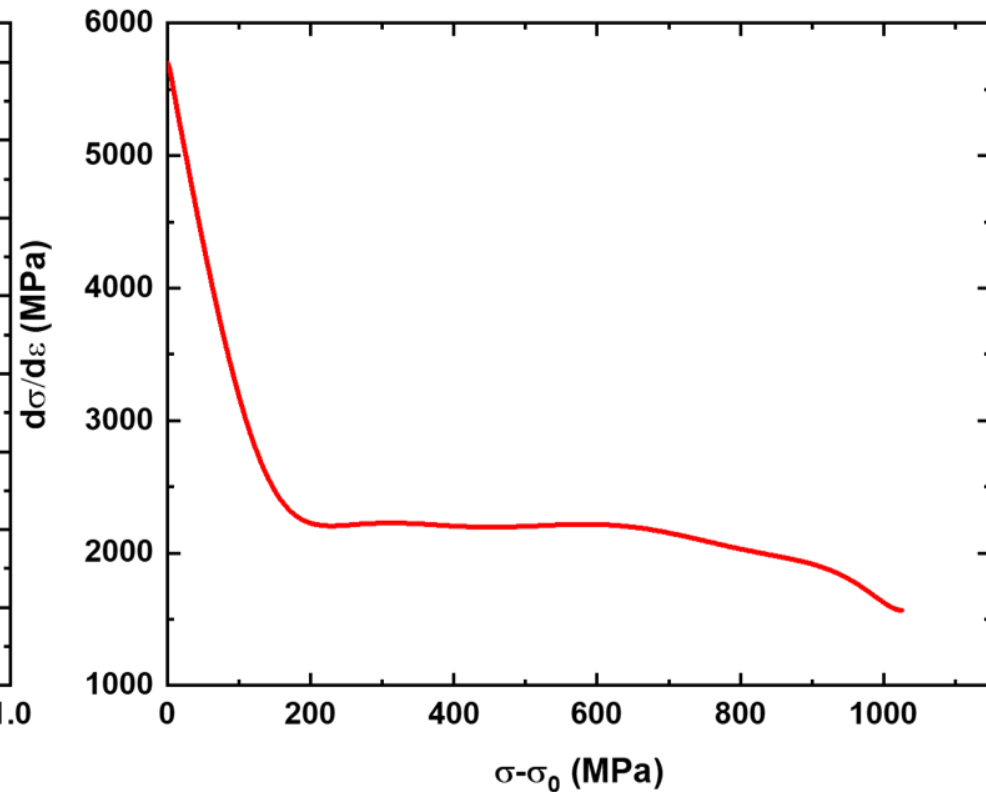
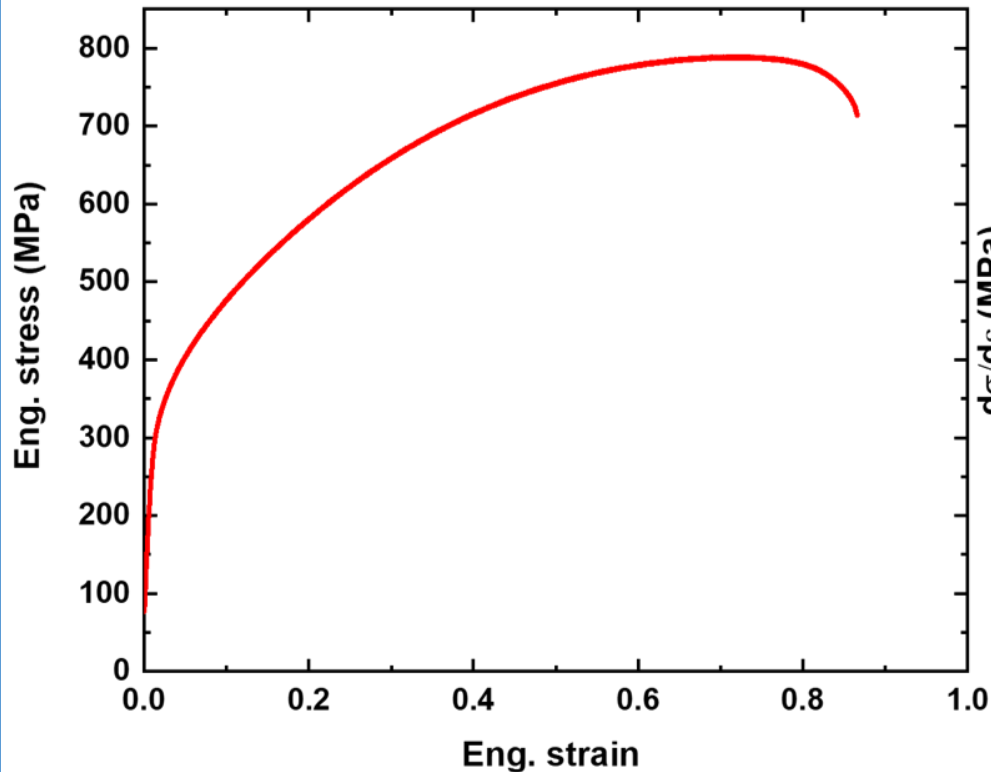
Element	Wt%
Si	0.19
Mn	30.9
Cr	9.18
Co	9.80
Fe	balance

- Single phase microstructure
- No elemental segregation
- Unstained well annealed structure
- Silicon doping increased the gamma phase stability



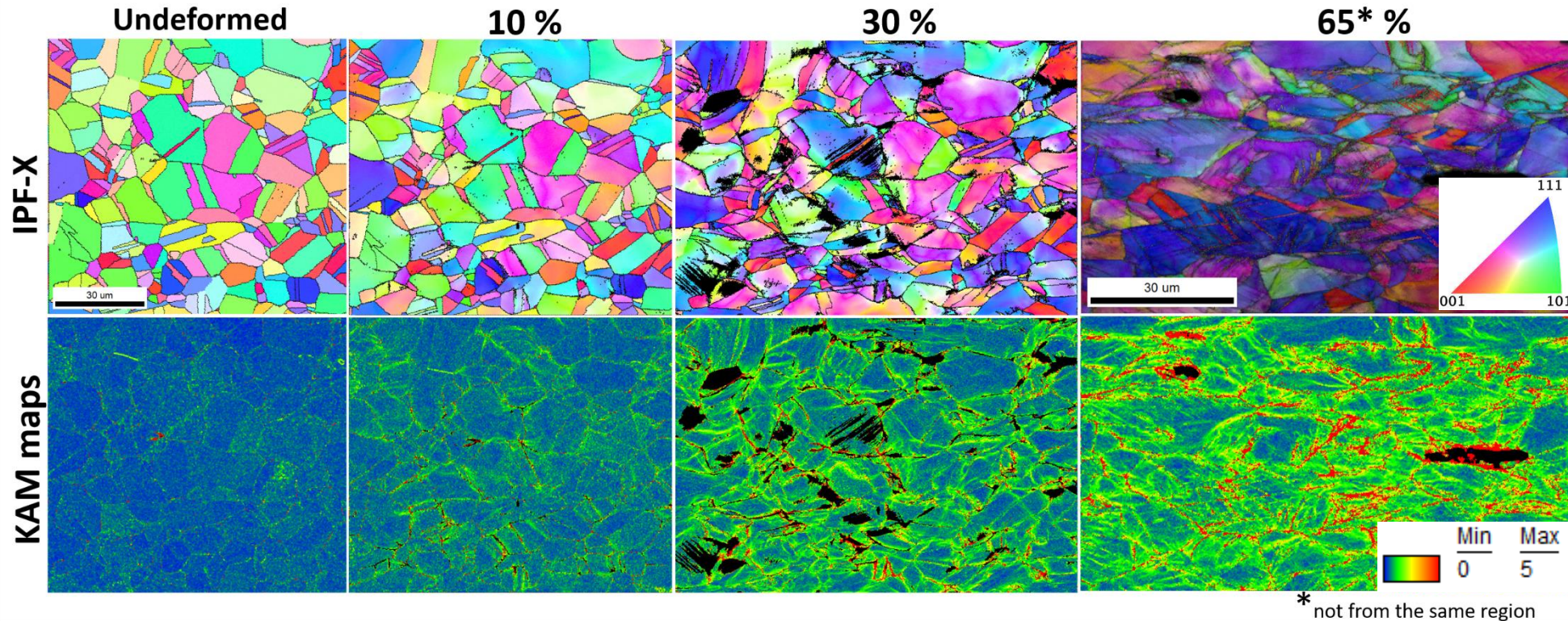
Mechanical behaviour at static strain rate (10^{-3} s^{-1})

Results & Discussion



22 %  75 % 112 %

- High ductility and ultimate tensile strength
- Sustained work hardening as indicated from the plateau of Kocks-Mecking plot
- Plateau indicate the operation of secondary deformation mechanism along with slip



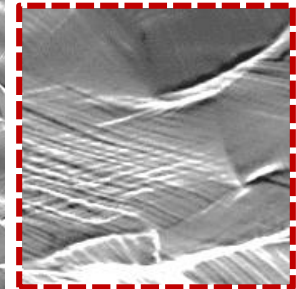
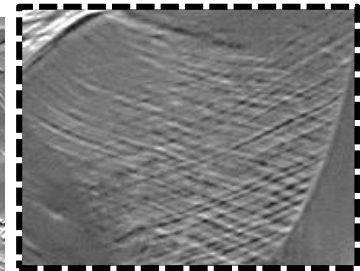
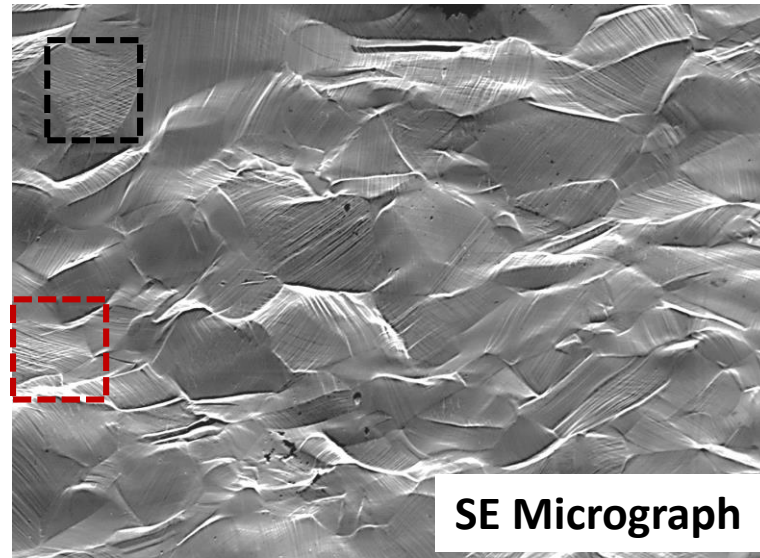
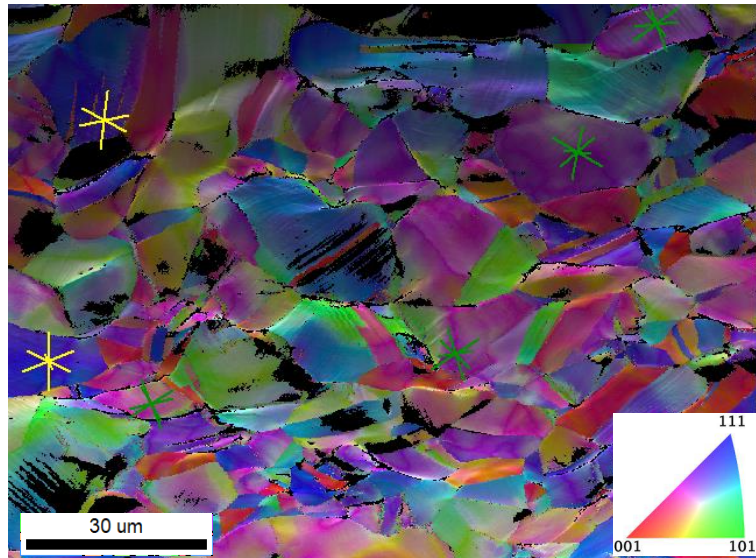
* not from the same region

- No deformation induced gamma to epsilon transformation
- High misorientation near the grain boundaries
- Reorientation towards $\langle 111 \rangle$ fibre
- High misorientation near grain boundaries indicate planer slip



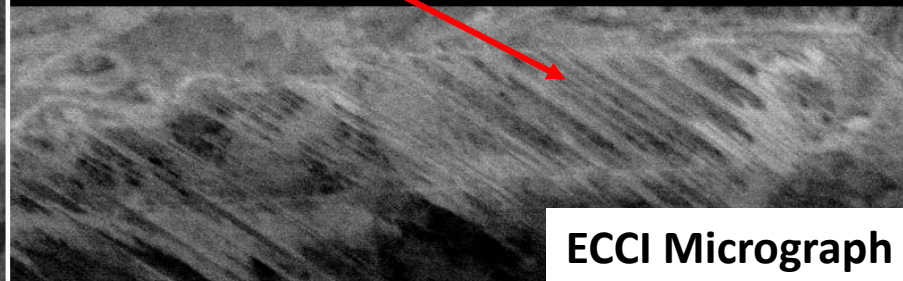
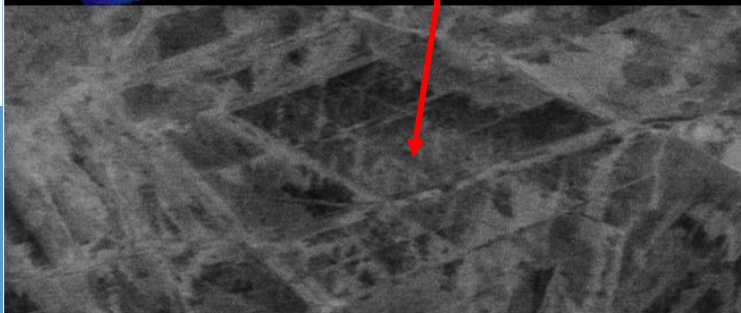
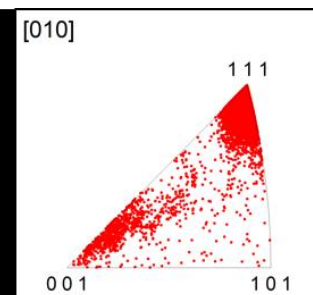
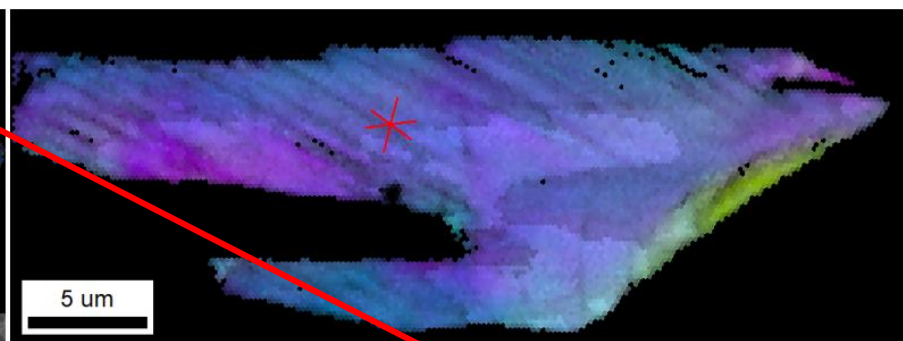
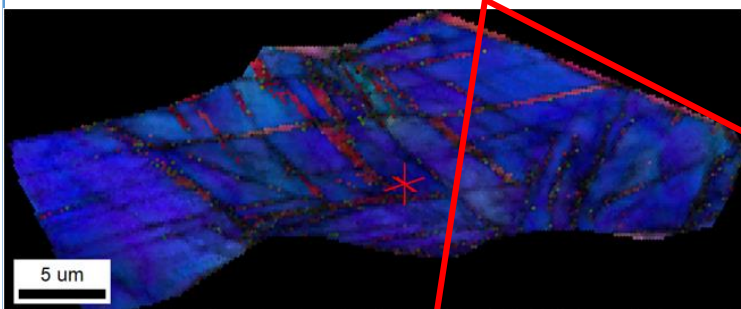
Post marten microstructure evaluation

Multiple slip traces

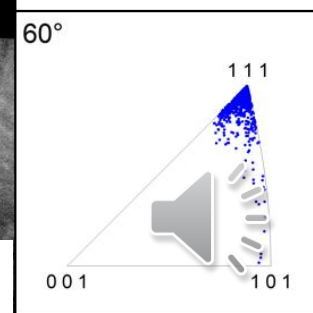


SE Micrograph

IPF-X after 30% strain with (111) plane traces,
Bundles of **nano and intersecting twins** as observed from ECCI

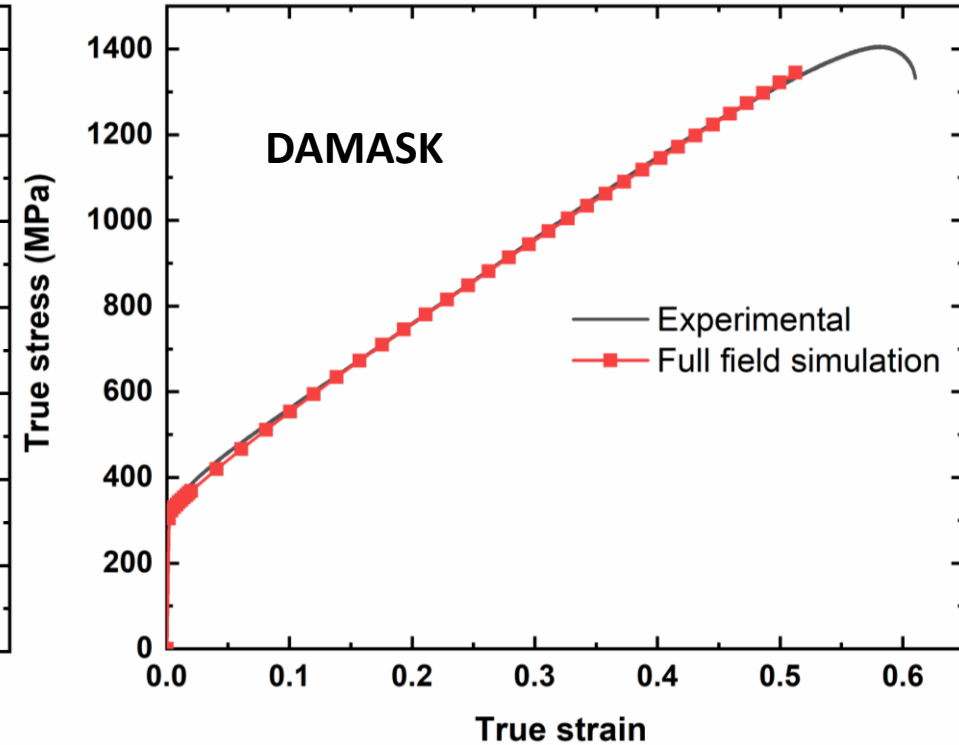
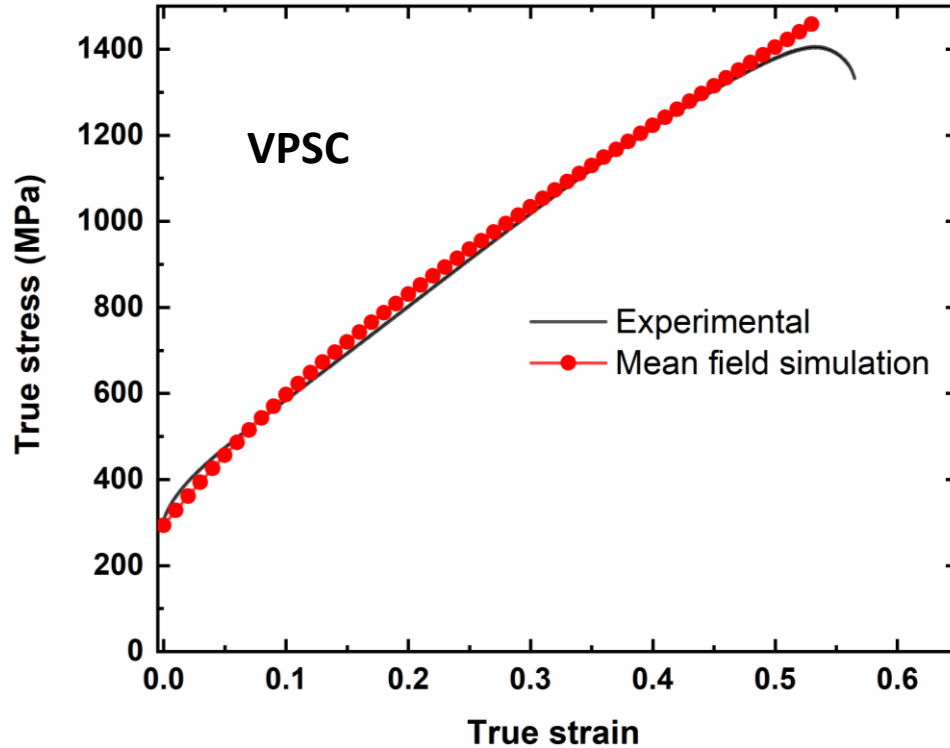


ECCI Micrograph



Mean & Full field crystal plasticity simulations

- *Stress strain response prediction*

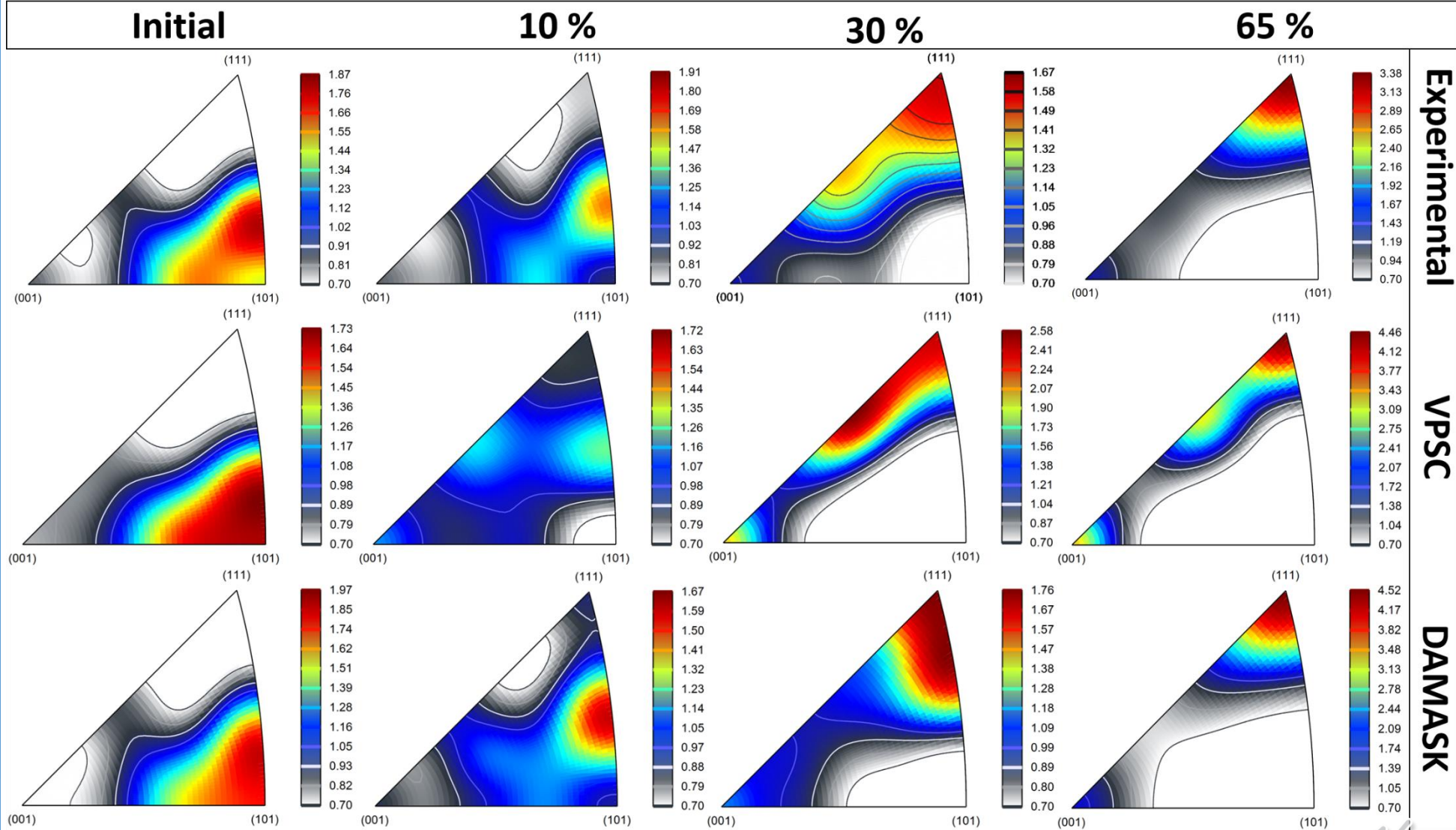


- Good correlation between experimental and simulated outputs



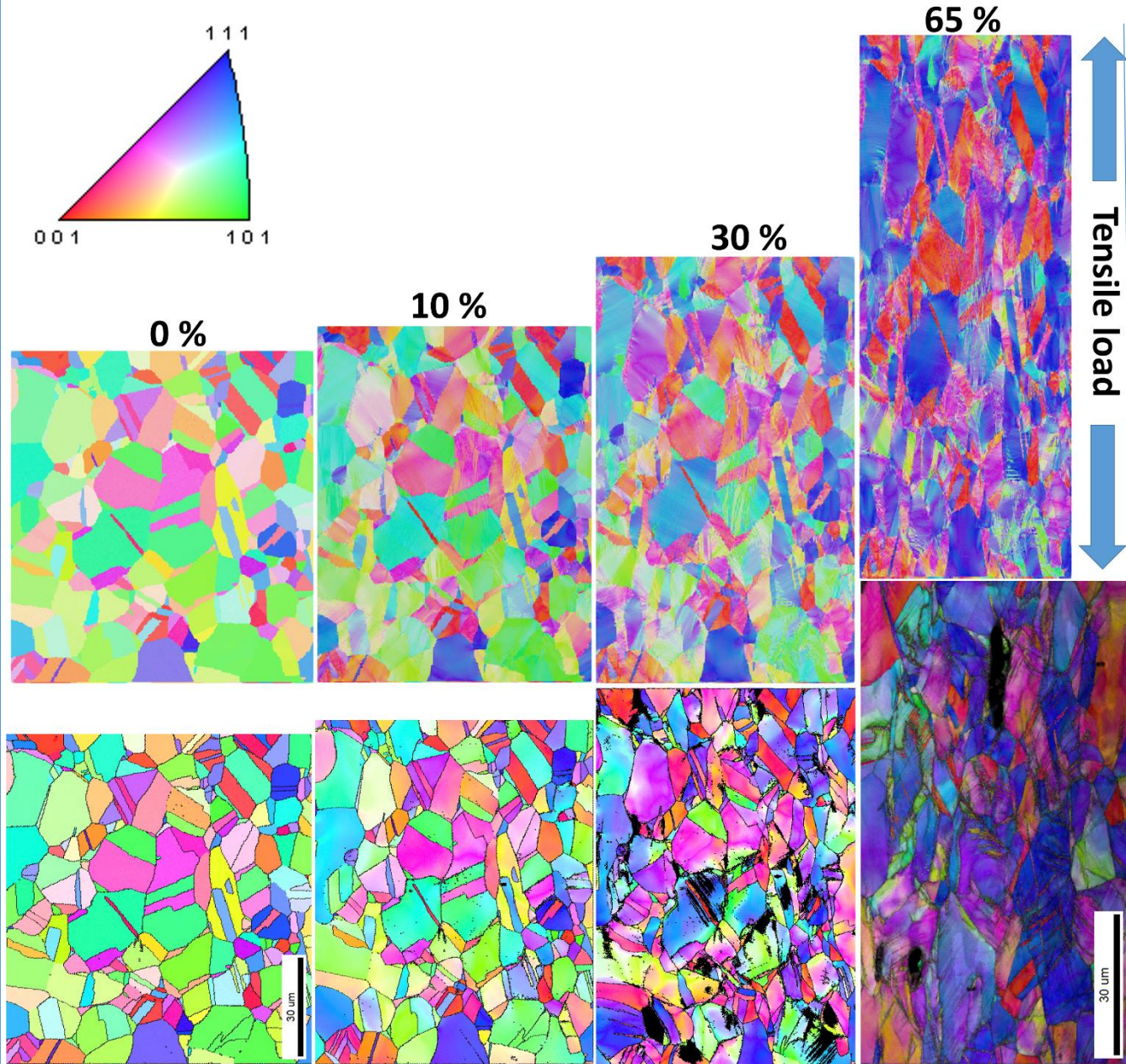
Mean & Full field crystal plasticity simulations

- *Texture evolution prediction*



- **Excellent texture evolution prediction**





- Excellent grain to grain correlation
- Excellent Intragranular Misorientation prediction
- Further correlations of orientations with stress and strain accommodation, slip and twin system activities are being carried out



Summary

- Silicon doping increased the gamma phase stability
- TRIP effect got suppressed rather TWIP effect was observed with bundles of nano twins imparting superior ductility and strength.
- Grains having $\langle 111 \rangle$ parallel to tensile direction deformation by more than one slip system and show twinning. Other orientations primarily deformed by slip as observed from slip traces.
- In situ experiment coupled with full field crystal plasticity simulations offers a high throughput procedure to reduce further experiments and predict microstructure sensitive and micro-mechanism guided deformation and damage behaviour of complex concentrated alloys.

Acknowledgement

- Texture – Microstructure – Stress laboratory, IIT Kanpur
- Department of Materials Science and Engineering, IIT Kanpur

